



#### **40V COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET**

### **Product Summary**

Device	V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub> max T <sub>A</sub> = +25°C (Note 7 & 9)
Q1	40V	25mΩ @ V <sub>GS</sub> = 10V	7.5A
Qi	40 V	40mΩ @ V <sub>GS</sub> = 4.5V	6.2A
Q2 -40V		25mΩ @ V <sub>GS</sub> = -10V	-7.3A
QZ	<del>-4</del> 0 v	45mΩ @ V <sub>GS</sub> = -4.5V	-5.7A

### **Description and Applications**

This MOSFET has been designed to ensure that RDS(on) of N and P channel FET are matched to minimize losses in both arms of the bridge. The DMC4040SSDQ is optimized for use in 3 phases brushless DC motor circuits (BLDC), CCFL backlighting.

- · 3 phases BLDC motor
- CCFL backlighting

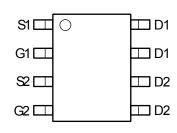
### **Features and Benefits**

- Reduced Footprint with Two Discrete Devices in Single SO-8
- Low On-Resistance
- Fast Switching Speed
- Low Input/Output Leakage
- Lead-Free Finish; RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability
- PPAP Available (Note 4)

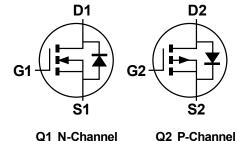
#### **Mechanical Data**

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- · Terminals Connections: See diagram below
- Terminals: Finish Matte Tin annealed over Copper lead frame.
   Solderable per MIL-STD-202, Method 208 (3)
- Weight: 0.074 grams (approximate)





Top View



Top View

Equivalent Circuit

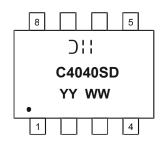
#### Ordering Information (Note 4 & 5)

Part Number	Compliance	Case	Packaging
DMC4040SSDQ-13 Automotive		SO-8	2,500/Tape & Reel

Notes:

- 1. EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant. All applicable RoHS exemptions applied.
- 2. See http://www.diodes.com/quality/lead\_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. Automotive products are AEC-Q101 qualified and are PPAP capable. Automotive, AEC-Q101 and standard products are electrically and thermally the same, except where specified. For more information, please refer to http://www.diodes.com/quality/product\_grade\_definitions/.
- 5. For packaging details, go to our website at http://www.diodes.com/products/packages.html.

## Marking Information



Oll = Manufacturer's Marking C4040SD = Product Type Marking Code YYWW = Date Code Marking YY = Year (ex: 13 = 2013) WW = Week (01 - 53)



# **Maximum Ratings** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

	Symbol	N-Channel - Q1	P-Channel - Q2	Units		
Drain-Source Voltage	Drain-Source Voltage			40	-40	V
Gate-Source Voltage			V <sub>GSS</sub>	±20	±20	V
		(Notes 7 & 9)	I <sub>D</sub>	7.5	-7.5	A
Continuous Drain Current	V <sub>GS</sub> = 10V	T <sub>A</sub> = +70°C (Notes 7 & 9)		5.8	-5.8	
Continuous Diain Current		(Notes 6 & 9)		5.7	-5.7	
		(Notes 6 & 10)		6.8	-6.8	
Pulsed Drain Current V <sub>GS</sub> = 10V		(Notes 8 & 9)	I <sub>DM</sub>	29.0	-29.0	Α
Continuous Source Current (Body diode) (Notes 7 & 9)		(Notes 7 & 9)	Is	3.0	-3.0	Α
Pulsed Source Current (Body diode) (Notes 8 & 9)		I <sub>SM</sub>	29.0	-29.0	Α	

# Thermal Characteristics ( $@T_A = +25^{\circ}C$ , unless otherwise specified.)

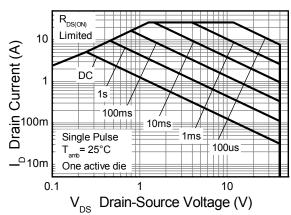
Characteristic	Symbol	N-Channel - Q1	P-Channel - Q2	Unit	
Develop	(Notes 6 & 9)		1.: 1		
Power Dissipation Linear Derating Factor	(Notes 6 & 10)	P <sub>D</sub>	1.8 14.3		W mW/°C
	(Notes 7 & 9)		2.14 17.2		
	(Notes 6 & 9)		100 70 58		°C/W
Thermal Resistance, Junction to Ambient	(Notes 6 & 10)	R <sub>0JA</sub>			
	(Notes 7 & 9)				
Thermal Resistance, Junction to Lead (Notes 9 & 11)		$R_{\theta JL}$	51		
Operating and Storage Temperature Range	T <sub>J,</sub> T <sub>STG</sub>	-55 to	+150	°C	

Notes:

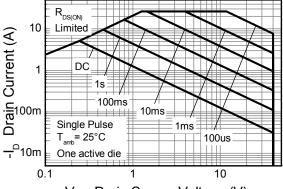
- 6. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
- 7. Same as note (6), except the device is measured at  $t \le 10$  sec.
- 8. Same as note (6), except the device is pulsed with D= 0.02 and pulse width 300 µs. The pulse current is limited by the maximum junction temperature.
- 9. For a dual device with one active die.
- 10. For a device with two active die running at equal power.
- 11. Thermal resistance from junction to solder-point (at the end of the drain lead).



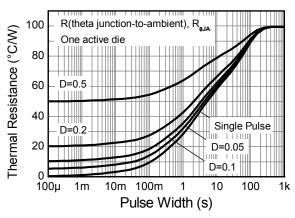
## **Thermal Characteristics**



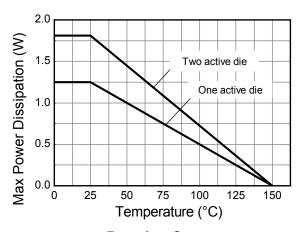
N-channel Safe Operating Area



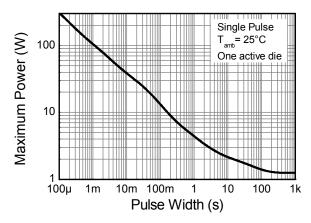
 ${}^{-}V_{_{\mathrm{DS}}}$  Drain-Source Voltage (V) **P-channel Safe Operating Area** 



**Transient Thermal Impedance** 



**Derating Curve** 



**Pulse Power Dissipation** 



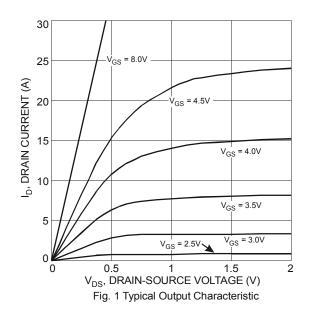
## Electrical Characteristics – Q1 N-Channel (@TA = +25°C, unless otherwise specified.)

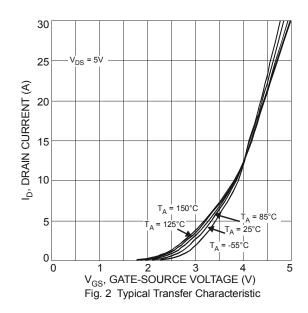
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	40	_	_	V	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	1.0	μA	V <sub>DS</sub> = 40V, V <sub>GS</sub> = 0V	
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS							
Gate Threshold Voltage	$V_{GS(th)}$	0.8	1.3	1.8	V	I <sub>D</sub> = 250μA, V <sub>DS</sub> = V <sub>GS</sub>	
Static Drain Source On Registence (Note 12)	Б		0.013	0.025	Ω	$V_{GS} = 10V, I_D = 3$	3A
Static Drain-Source On-Resistance (Note 12)	R <sub>DS (ON)</sub>	_	0.028	0.040	12	$V_{GS} = 4.5V, I_D =$	3A
Forward Transconductance (Notes 12 & 13)	g <sub>fs</sub>	_	12.6	_	S	$V_{DS} = 5V, I_{D} = 3A$	
Diode Forward Voltage (Note 8)	V <sub>SD</sub>	_	0.7	1.0	V	I <sub>S</sub> = 1A, V <sub>GS</sub> = 0V	
DYNAMIC CHARACTERISTICS (Note 13)			•	•	•		
Input Capacitance	Ciss	_	1790	_	pF	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V F = 1MHz	
Output Capacitance	Coss	_	160	_	pF		
Reverse Transfer Capacitance	C <sub>rss</sub>	_	120	_	pF		
Gate Resistance	$R_g$	_	1.03	_	Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V, f = 1MHz	
Total Gate Charge (Note 14)	Qg	_	16.0	_	nC	V <sub>GS</sub> = 4.5V	
Total Gate Charge (Note 14)	Qg	_	37.6	_	nC		V <sub>DS</sub> = 20V
Gate-Source Charge (Note 14)	Q <sub>gs</sub>	_	7.8	_	nC	$V_{GS} = 10V$ $I_D = 3A$	
Gate-Drain Charge (Note 14)	$Q_{gd}$	_	6.6	_	nC		
Turn-On Delay Time (Note 14)	t <sub>D(on)</sub>	_	8.1	_	ns	V <sub>DD</sub> = 20V, V <sub>GS</sub> = 10V I <sub>D</sub> = 3A	
Turn-On Rise Time (Note 14)	t <sub>r</sub>	_	15.1	_	ns		
Turn-Off Delay Time (Note 14)	t <sub>D(off)</sub>	_	24.3	_	ns		
Turn-Off Fall Time (Note 14)	t <sub>f</sub>	_	5.3	_	ns		

Notes:

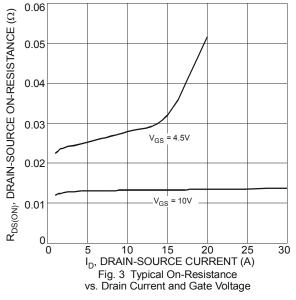
- 12. Measured under pulsed conditions. Pulse width  $\leq$  300 $\mu$ s; duty cycle  $\leq$  2%
- 13. For design aid only, not subject to production testing.
  14. Switching characteristics are independent of operating junction temperatures.

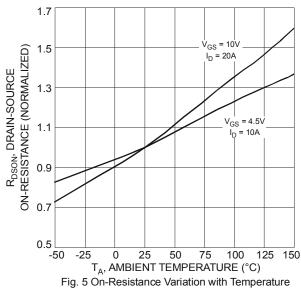
# Typical Characteristics - Q1 N-Channel











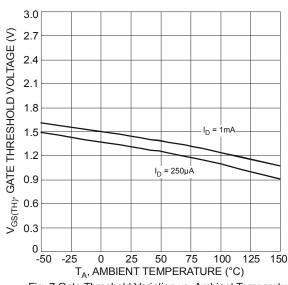
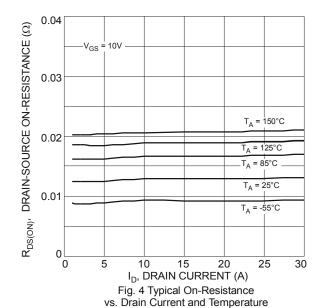


Fig. 7 Gate Threshold Variation vs. Ambient Temperature



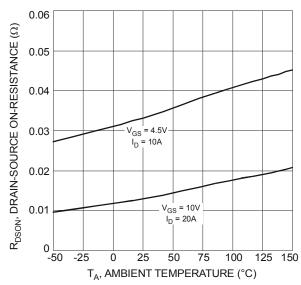


Fig. 6 On-Resistance Variation with Temperature

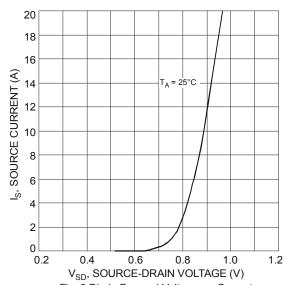
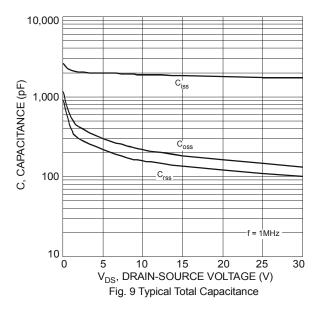
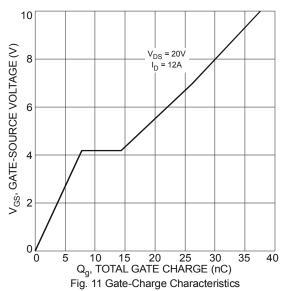
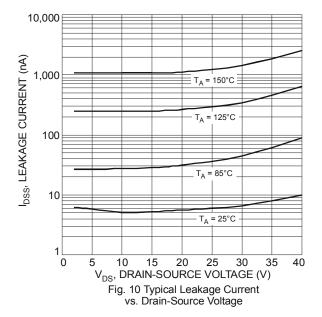


Fig. 8 Diode Forward Voltage vs. Current











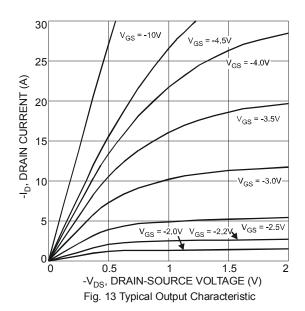
## Electrical Characteristics – Q2 P-Channel (@T<sub>A</sub> = +25°C, unless otherwise specified.)

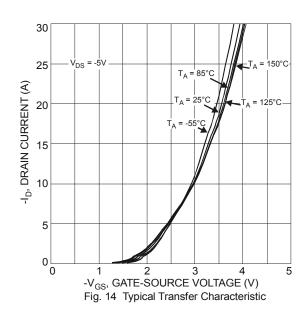
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-40	_	_	V	I <sub>D</sub> = -250μA, V <sub>GS</sub> = 0V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	-1.0	μA	V <sub>DS</sub> = -40V, V <sub>GS</sub> = 0V	
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS							
Gate Threshold Voltage	$V_{GS(th)}$	-0.8	-1.3	-1.8	V	I <sub>D</sub> = -250μA, V <sub>DS</sub> = V <sub>GS</sub>	
Statio Drain Source On Registence (Note 15)	J		0.018	0.025	Ω	V <sub>GS</sub> = -10V, I <sub>D</sub> = -3A	
Static Drain-Source On-Resistance (Note 15)	R <sub>DS (ON)</sub>	_	0.030	0.045	12	$V_{GS} = -4.5V, I_D =$	: -3A
Forward Transconductance (Notes 15 & 16)	g <sub>fs</sub>	_	16.6	_	S	V <sub>DS</sub> = -5V, I <sub>D</sub> = -3A	
Diode Forward Voltage (Note 15)	V <sub>SD</sub>	_	-0.7	-1.0	V	I <sub>S</sub> = -1A, V <sub>GS</sub> = 0V	
DYNAMIC CHARACTERISTICS (Note 16)							
Input Capacitance	C <sub>iss</sub>		1643	_	pF	V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V F = 1MHz	
Output Capacitance	Coss	-	179	_	pF		
Reverse Transfer Capacitance	C <sub>rss</sub>	_	128	_	pF		
Gate Resistance	$R_g$	_	6.43	_	Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V, f = 1MHz	
Total Gate Charge (Note 17)	Qg	_	14.0	_	nC	$V_{GS} = -4.5V$	
Total Gate Charge (Note 17)	Qg		33.7	_	nC		V <sub>DS</sub> = -20V
Gate-Source Charge (Note 17)	Q <sub>gs</sub>		5.5	_	nC	V <sub>GS</sub> = -10V	
Gate-Drain Charge (Note 17)	Q <sub>gd</sub>	-	7.3	_	nC		
Turn-On Delay Time (Note 17)	t <sub>D(on)</sub>	_	6.9	_	ns	$V_{DD} = -20V, V_{GS} = -10V$ $I_{D} = -3A$	
Turn-On Rise Time (Note 17)	t <sub>r</sub>	_	14.7	_	ns		
Turn-Off Delay Time (Note 17)	t <sub>D(off)</sub>	_	53.7	_	ns		
Turn-Off Fall Time (Note 17)	t <sub>f</sub>	_	30.9	_	ns		

Notes:

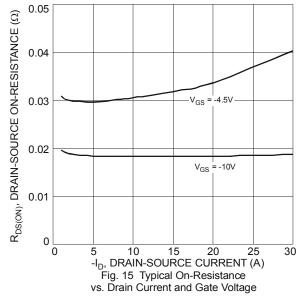
- 15. Measured under pulsed conditions. Pulse width  $\leq$  300µs; duty cycle  $\leq$  2%
- 16. For design aid only, not subject to production testing.17. Switching characteristics are independent of operating junction temperatures

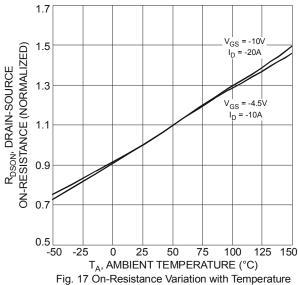
# Typical Characteristics - Q2 P-Channel











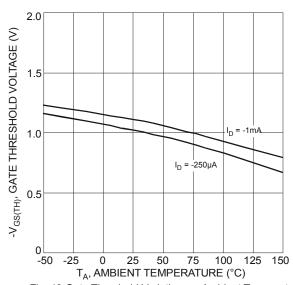
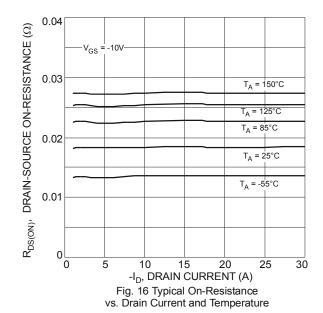
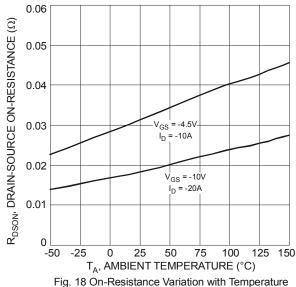


Fig. 19 Gate Threshold Variation vs. Ambient Temperature





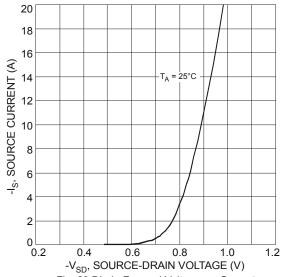
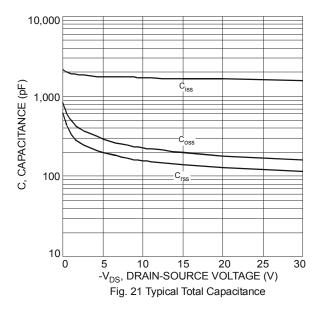
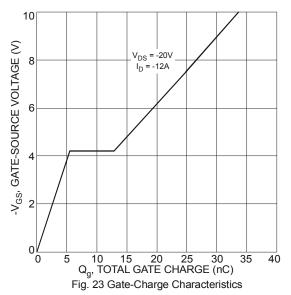
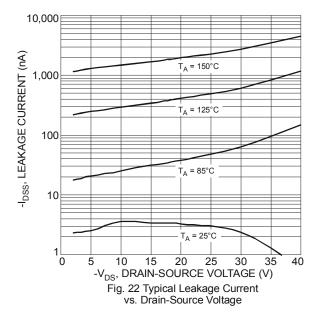


Fig. 20 Diode Forward Voltage vs. Current





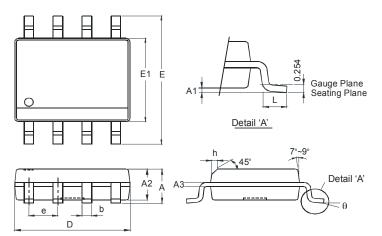






## **Package Outline Dimensions**

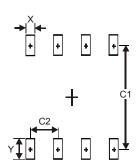
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for the latest version.



	SO-8					
Dim	Min	Max				
Α	-	1.75				
A1	0.10	0.20				
A2	1.30	1.50				
A3	0.15	0.25				
b	0.3	0.5				
D	4.85	4.95				
E	5.90	6.10				
E1	3.85	3.95				
е	1.27 Typ					
h	-	0.35				
L	0.62	0.82				
θ	0°	8°				
All Dimensions in mm						

## **Suggested Pad Layout**

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
Х	0.60
Y	1.55
C1	5.4
C2	1 27



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